TEST REPORT

Applicant:	Hanvon Ugee Technology Co., Ltd.
Address:	18/F, 19/F, 20/F， No.1 Bldg., Longhua Digital Intelligent Manufacturing Center, No. 238 Longsheng Road, Longhua District, Shenzhen
Equipment Type:	Magic Ultra 14
Model Name:	MDP1411(refer to section 2.3)
Brand Name:	XPPen
FCC ID:	2A2JY-MDP1411
Test Standard:	47 CFR Part 15 Subpart B ANSI C63.4-2014
Sample Arrival Date:	Jul. 10, 2026
Test Date:	Jul. 14, 2026 - Jul. 30, 2026
Date of Issue:	Oct. 14, 2026

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Gu shuai zhen **Checked by:** Zong Liyao **Approved by:** Liao Jianming (Technical Director)

Gu shuai zhen. Zong Liyao

Revision History

Version	Issue Date	Revisions
Rev. 01	Sep. 17, 2026	Initial Issue
Rev. 02	Oct. 14, 2026	Update Chapter 1.2

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	601, Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☐ Building 2, Intelligent Connected Vehicle Industrial Park, No.55, Xiangshan Road, Luotian Community, Yanluo Sub-district, Bao'an District, Shenzhen, Guangdong
	☑ 1/F., Building B, Ganghongji High-Tech Intelligent Industrial Park, No.1008, Songbai Road, Yangguang Community, Xili Subdistrict, Nanshan District, Shenzhen, Guangdong
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196 and FCC registration number is 935607.The certification body is American Association for Laboratory Accreditation (A2LA).

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Hanvon Ugee Technology Co., Ltd.
Address	18/F, 19/F, 20/F, No.1 Bldg., Longhua Digital Intelligent Manufacturing Center, No. 238 Longsheng Road, Longhua District, Shenzhen

2.2 Manufacturer Information

Manufacturer	Hanvon Ugee Technology Co., Ltd.
Address	18/F, 19/F, 20/F, No.1 Bldg., Longhua Digital Intelligent Manufacturing Center, No. 238 Longsheng Road, Longhua District, Shenzhen

2.3 General Description for Equipment under Test (EUT)

EUT Name	Magic Ultra 14
Model Name Under Test	MDP1411
Series Model Name	MDP1412, MDP1413, MDP1414, MDP1415
Description of Model name differentiation	Only the model name is different. (this information provided by the applicant).
Hardware Version	N/A
Software Version	N/A
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Ancillary Equipment 1	Battery	
	Brand Name	N/A
	Model No.	HQ-8612NA
	Serial No.	N/A
	Capacity	Rated:10840mAh, Typical: 1120mAh,
	Rated Voltage	3.7 V
	Limit Charge Voltage	N/A
	Manufacturer	Dongguan Amperex Technology Limited
Ancillary Equipment 2	USB Cable	
	Model No.	/
	Length (Approx.)	1.5m
Ancillary Equipment 3	Stylus Pen	
	Model No.	/

2.5 Technical Information

Network and Wireless connectivity	Bluetooth (BR+EDR+BLE) WIFI 802.11a, 802.11b, 802.11g, 802.11n(HT20/HT40), 802.11ac(VHT20/VHT40/VHT80/VHT160), 802.11ax(HE20/HE40/HE80/ HE160)
Classification of equipment	Class B

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	--
2	Conducted Emission, AC Ports	15.107	Pass	--

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-150 KHz)-AMN	3.36 dB
Conducted emissions (150 kHz-30 MHz)-AMN	2.92 dB
Radiated emissions (30 MHz-1 GHz)	4.24 dB
Radiated emissions (1 GHz-6 GHz)	5.10 dB
Radiated emissions (6 GHz-18 GHz)	5.30 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
WIFI Router	ASUS	ROG Rapture GT-BE98 Pro	N/A	N/A	N/A	☒
Bluetooth Earphone	SAMSUNG	Gear Circle	N/A	N/A	N/A	☒
Type-C Earphone	OPPO	MH156	N/A	1.12m	N/A	☒
Laptop	Lenovo	N/A	N/A	N/A	N/A	☒
Data connector	HBR	Type-C to USB 3.0	N/A	N/A	N/A	☒
USB disk	Sandisk	CZ73-32G	N/A	N/A	32G	☒
Type-C To DP Cable	N/A	N/A	N/A	N/A	N/A	☒
Monitor	AOC	N/A	N/A	N/A	N/A	☒
Keyboard	N/A	N/A	N/A	N/A	N/A	☒
Adapter	N/A	N/A	N/A	N/A	N/A	☒
Capacitive stylus	N/A	N/A	N/A	N/A	N/A	☒

4.2 Test Configurations

All test modes of EUT are listed in the table below.

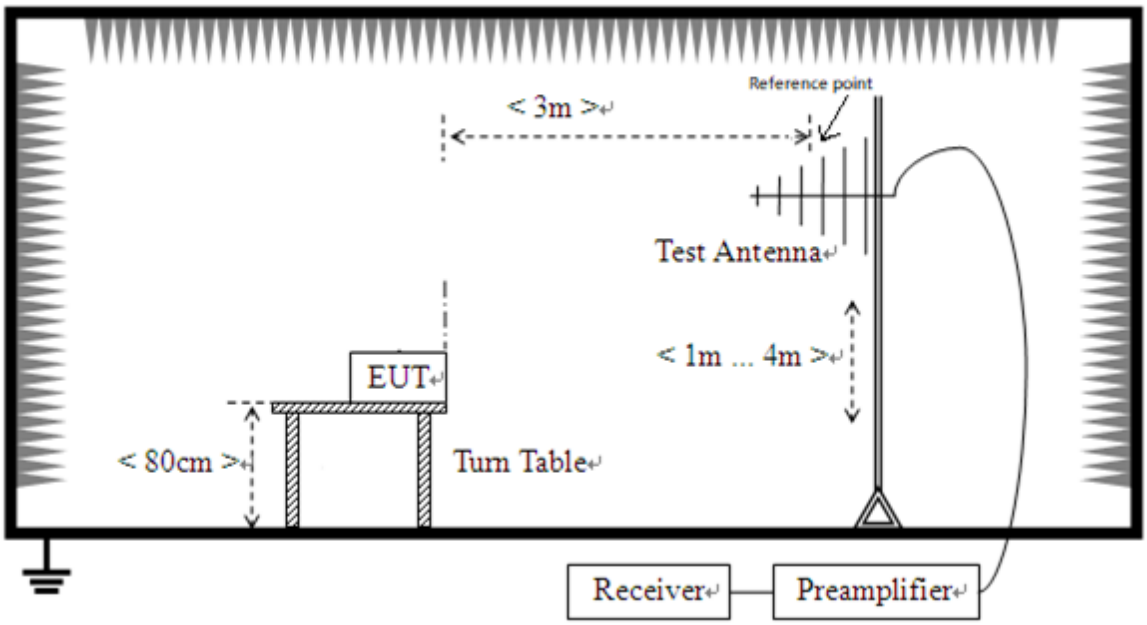
Test Mode Configuration	Description
Mode 1	The H-Pattern Test Mode EUT + Adapter + Type-c Cable + Battery + Keyboard + Capacitive stylus + TF Card
Mode 2	The Type-C Earphone Test Mode EUT + Adapter + Type-c Cable + Battery + Keyboard + Capacitive stylus +Color Bar(1Khz Tone) + Type-C Earphone
Mode 3	The DP Test Mode EUT + Adapter + Type-c Cable + Battery + Keyboard + Capacitive stylus +Color Bar(1Khz Tone) + Type-C To DP Cable + Monitor
Mode 4	The Rear Camera Test Mode EUT + Adapter + Type-c Cable + Battery + Keyboard + Capacitive stylus + TF Card + Rear Camera
Mode 5	The Front Camera Test Mode

	EUT + Adapter + Type-c Cable + Battery + Keyboard + Capacitive stylus + TF Card + Front Camera
Mode 6	Type-c Data Transmission Test Mode EUT + Type-c Cable + Battery + Keyboard + Capacitive stylus + Laptop + TF Card
Mode 7	OTG Data Transmission Test Mode EUT + Battery + Data connector + USB disk + TF Card

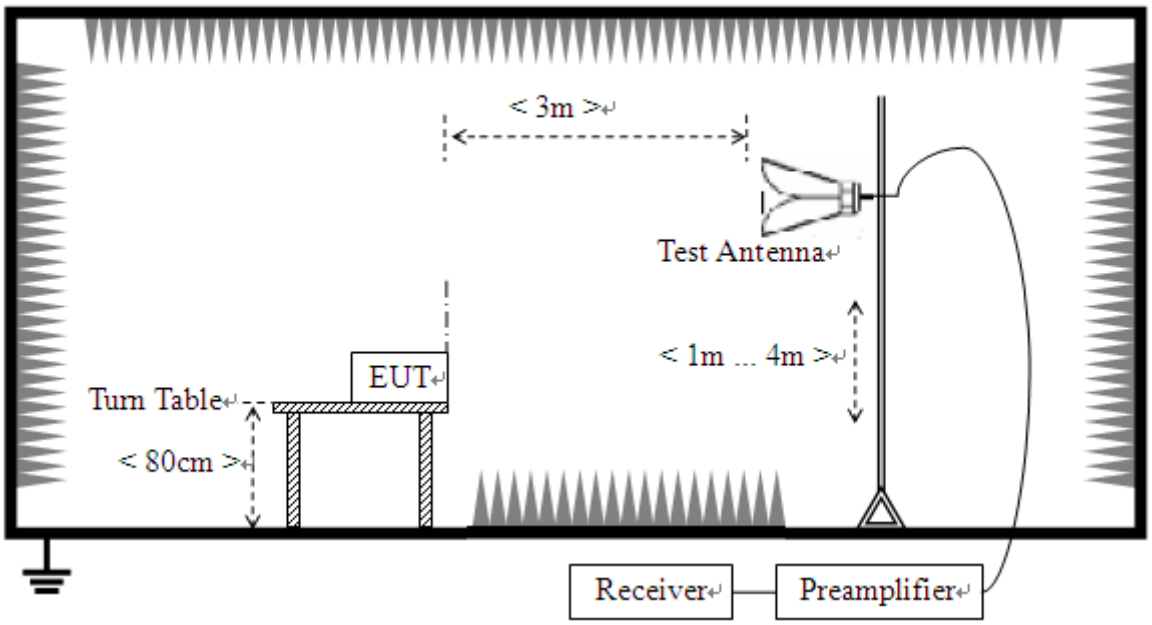
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 7	1
Conducted Emission, AC Ports	Mode 1~Mode 5	1
Note: All operation modes were tested, but only test data of the worst mode was presented in this report.		

4.3 Test Setups

Test Setup 1

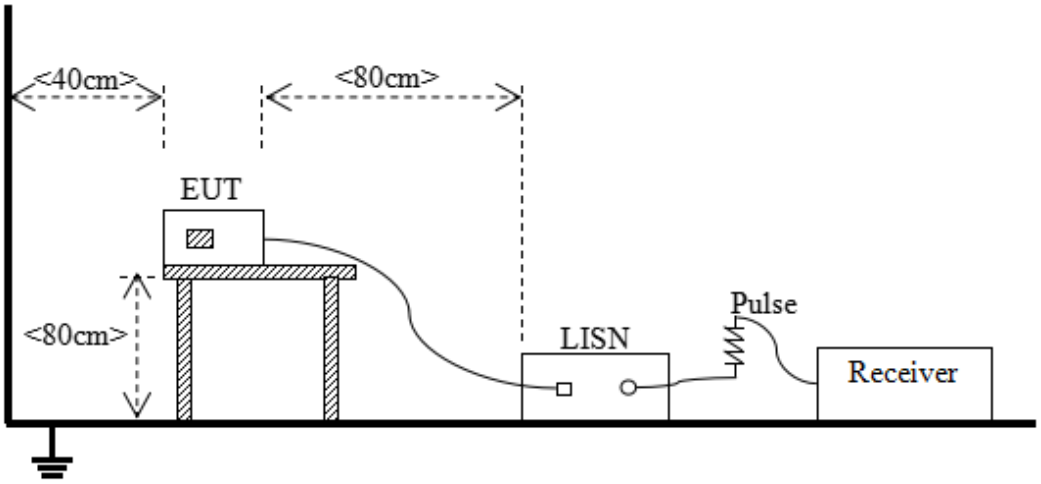


Radiated Emission (30 MHz-1 GHz)



Radiated Emission (above 1 GHz)

Test Setup 2



Conducted Emissions, AC Ports

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class A (at 3 m)
	Field Strength (μV/m)	Field Strength (dBμV/m)	Field Strength (dBμV/m)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60
NOTE: 1) Field Strength (dBμV/m) = 20*log [Field Strength (μV/m)]. 2) In the emission tables above, the tighter limit applies at the band edges. 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.			

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)	Class B (at 3 m)			Class A (at 3 m)	
	Field Strength (μV/m)	Field Strength Average (dBμV/m)	Field Strength Peak (dBμV/m)	Field Strength Average (dBμV/m)	Field Strength Peak (dBμV/m)
1 - F_M	500	54	74	60	80
Note 1: The highest measurement frequency, F_M, in GHz, shall be determined as next Table. Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula: $L_{3m} = L_{10m} + 20*\log(d_{10m}/d_{3m})$ Where: L_{3m} is Average Class A limit at 3m; L_{10m} is Average Class A limit at 10m; d_{10m} is Measurement distance in 10m; d_{3m} is Measurement distance in 3m. For this case: L_{3m} = 49.5 + 20*log(10/3)=60 (dBμV/m).					

Highest internal frequency (F_X)	Highest measurement frequency (F_M)
$F_X \leq 108$ MHz	1 GHz
108 MHz ≤ $F_X \leq 500$ MHz	2 GHz
500 MHz ≤ $F_X \leq 1$ GHz	5 GHz
$F_X \geq 1$ GHz	5 *F_X or 40 GHz, whichever is lower.
Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.	

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360°, and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for f ≥ 1 GHz, 100 kHz for f < 1 GHz

VBW ≥ RBW

Sweep = auto

Detector function = peak for f <1 GHz, peak & RMS Average for f ≥ 1 GHz

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.

NOTE:

1. Results (dBμV/m) = Reading (dBμV) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Margin = Limit - Results

5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dBμV)	Average (dBμV)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dBμV)	Average (dBμV)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

1) The lower limit shall apply at the band edges.
2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω/50 μH of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW ≥ RBW

Sweep = 10ms

Detector function =peak & Average

Trace = max hold

5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results (dBμV) = Reading (dBμV) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Margin = Limit - Results

ANNEX A TEST RESULTS

A.1 Radiated Emission

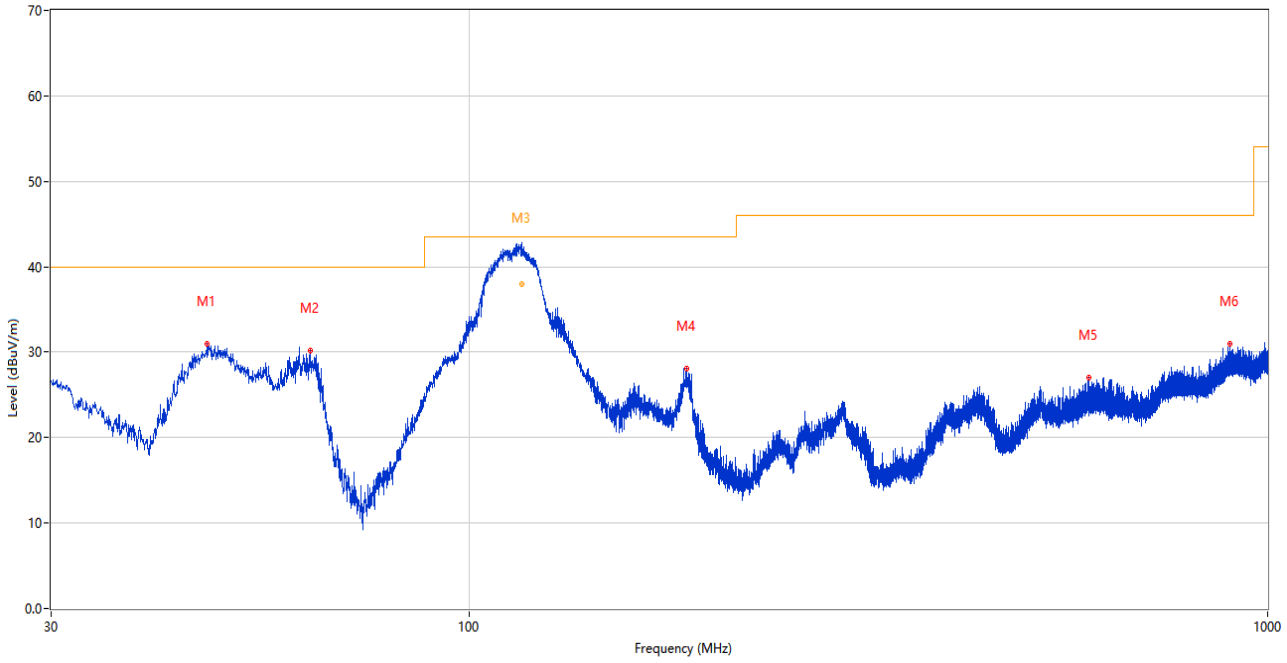
Note 1: The symbol of "--" in the table which means not application.

Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Sample No.	S13	Temperature	22.3℃
Humidity	50%RH	Pressure	99.5 kPa
Test Engineer	Tang Xuming	Test Date	2026.07.14

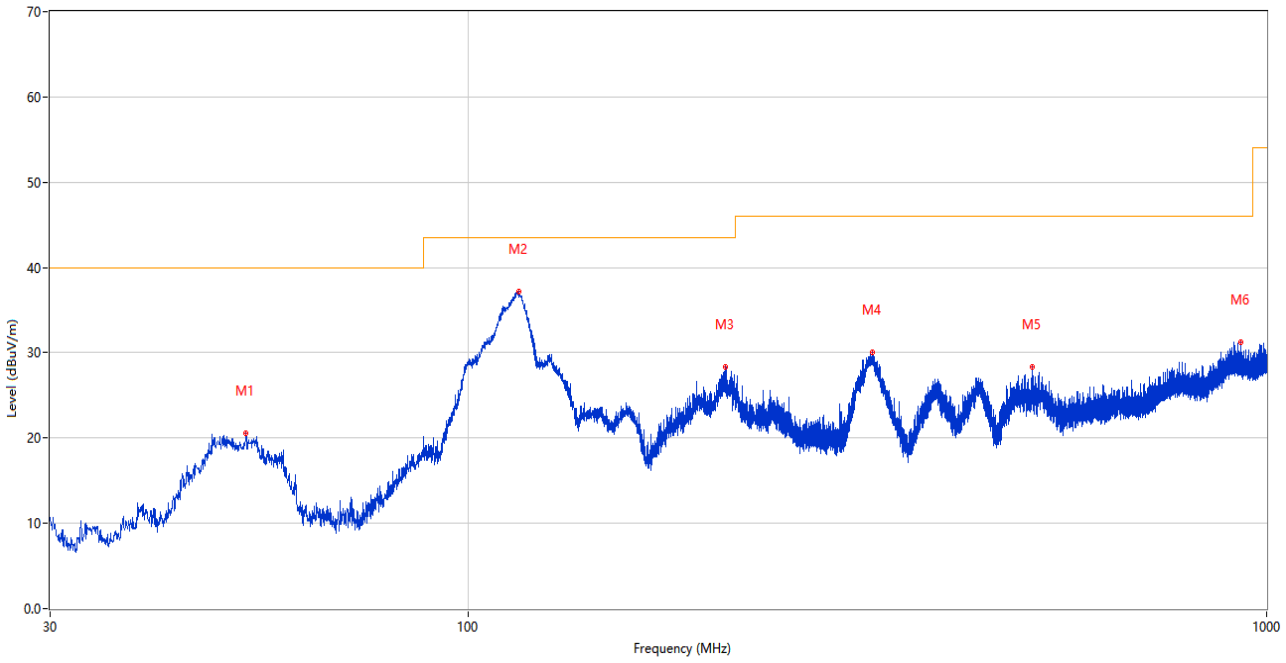
Test Mode 1

1) Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	47.072	30.97	-25.45	40.0	9.03	Peak	164.00	100	Vertical	Pass
2	63.271	30.23	-26.82	40.0	9.77	Peak	102.00	100	Vertical	Pass
3	116.528	41.66	-27.56	43.5	1.84	Peak	230.00	100	Vertical	N/A
3*	116.528	38.02	-27.56	43.5	5.48	QP	230.00	100	Vertical	Pass
4	187.334	28.12	-26.71	43.5	15.38	Peak	350.00	200	Vertical	Pass
5	597.256	27.04	-15.25	46.0	18.96	Peak	246.00	100	Vertical	Pass
6	896.356	30.92	-8.80	46.0	15.08	Peak	188.00	200	Vertical	Pass

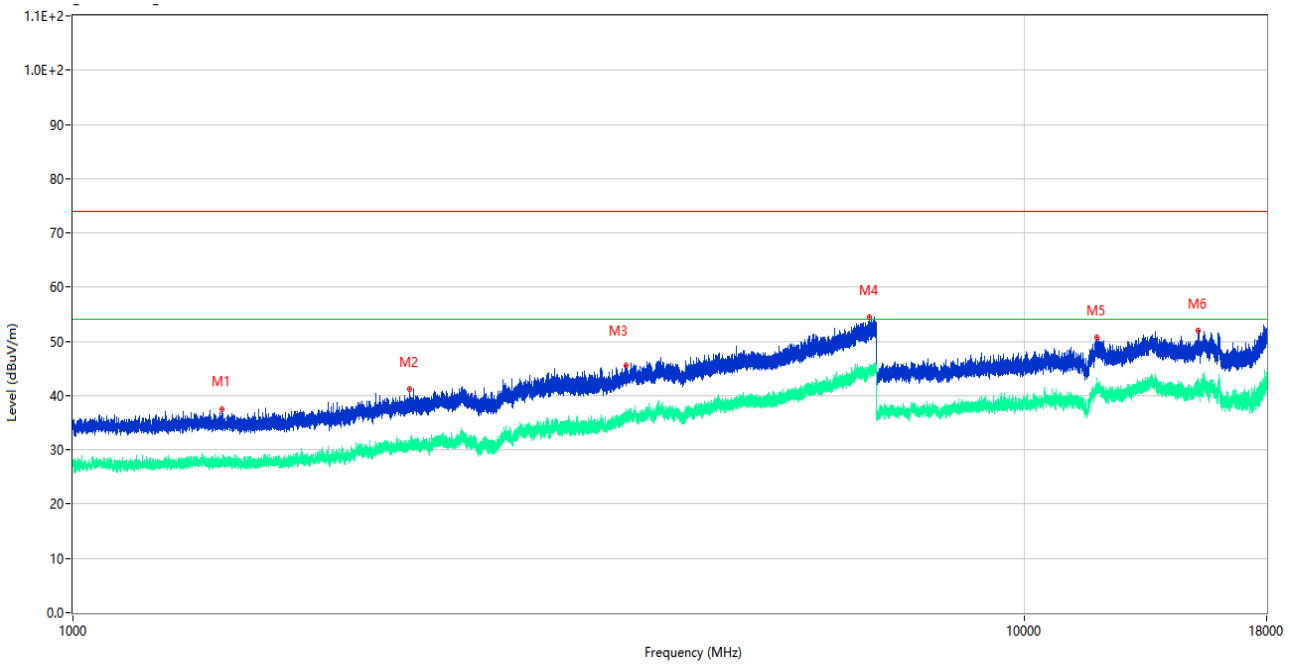
2) Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	52.795	20.63	-25.31	40.0	19.37	Peak	275.00	100	Horizontal	Pass
2	115.700	37.22	-27.40	43.5	6.28	Peak	248.00	200	Horizontal	Pass
3	210.420	28.41	-26.52	43.5	15.09	Peak	252.00	100	Horizontal	Pass
4	320.612	30.07	-22.96	46.0	15.93	Peak	155.00	100	Horizontal	Pass
5	508.210	28.30	-17.90	46.0	17.70	Peak	339.00	100	Horizontal	Pass
6	927.444	31.24	-8.66	46.0	14.76	Peak	13.00	100	Horizontal	Pass

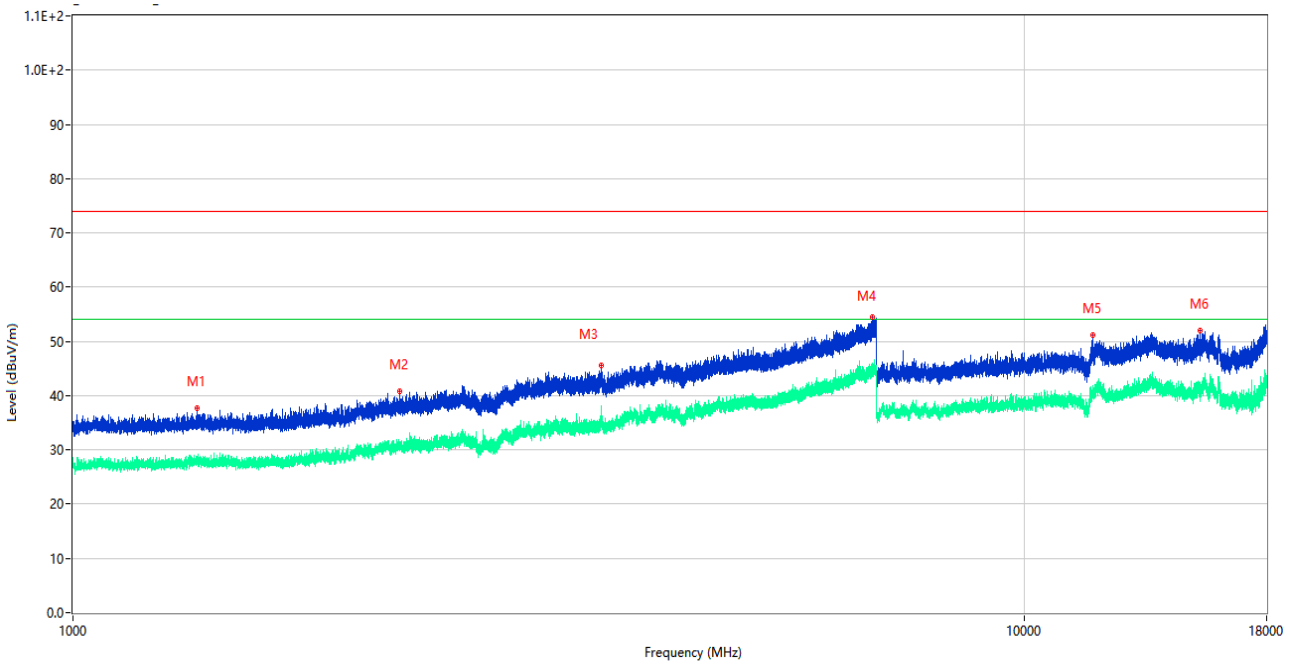
Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Below 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Bi-Log	SCHWARZBECK	VULB 9163	01414	2023.11.03	2026.11.02	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

3) Test Antenna Vertical, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1433.030	37.57	-17.80	74.0	36.43	Peak	144.00	100	Vertical	Pass
1**	1433.030	27.97	-17.80	54.0	26.03	AV	144.00	100	Vertical	Pass
2	2261.780	41.26	-14.56	74.0	32.74	Peak	324.00	100	Vertical	Pass
2**	2261.780	31.17	-14.56	54.0	22.83	AV	324.00	100	Vertical	Pass
3	3812.670	45.55	-6.19	74.0	28.45	Peak	219.00	100	Vertical	Pass
3**	3812.670	36.12	-6.19	54.0	17.88	AV	219.00	100	Vertical	Pass
4	6878.790	54.41	0.51	74.0	19.59	Peak	151.00	100	Vertical	Pass
4**	6878.790	45.24	0.51	54.0	8.76	AV	151.00	100	Vertical	Pass
5	11918.650	50.79	5.91	74.0	23.21	Peak	340.00	100	Vertical	Pass
5**	11918.650	40.52	5.91	54.0	13.48	AV	340.00	100	Vertical	Pass
6	15232.400	51.93	5.99	74.0	22.07	Peak	30.00	100	Vertical	Pass
6**	15232.400	41.51	5.99	54.0	12.49	AV	30.00	100	Vertical	Pass

4) Test Antenna Horizontal, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1352.040	37.77	-17.76	74.0	36.23	Peak	22.00	100	Horizontal	Pass
1**	1352.040	28.39	-17.76	54.0	25.61	AV	22.00	100	Horizontal	Pass
2	2207.960	40.74	-14.79	74.0	33.26	Peak	361.00	100	Horizontal	Pass
2**	2207.960	29.99	-14.79	54.0	24.01	AV	361.00	100	Horizontal	Pass
3	3596.750	45.67	-8.26	74.0	28.33	Peak	286.00	100	Horizontal	Pass
3**	3596.750	35.18	-8.26	54.0	18.82	AV	286.00	100	Horizontal	Pass
4	6924.010	54.39	0.69	74.0	19.61	Peak	320.00	100	Horizontal	Pass
4**	6924.010	44.44	0.69	54.0	9.56	AV	320.00	100	Horizontal	Pass
5	11815.250	51.10	4.79	74.0	22.90	Peak	126.00	100	Horizontal	Pass
5**	11815.250	40.82	4.79	54.0	13.18	AV	126.00	100	Horizontal	Pass
6	15306.651	51.95	6.21	74.0	22.05	Peak	37.00	100	Horizontal	Pass
6**	15306.651	42.15	6.21	54.0	11.85	AV	37.00	100	Horizontal	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
Frequency Above 1 GHz						
EMI Receiver	Keysight	N9038A	MY55330121	2025.12.26	2026.12.25	☒
Test Antenna-Horn	SCHWARZBECK	BBHA 9120D	02459	2023.10.26	2026.10.25	☒
Anechoic Chamber	EMC Electronic Co., Ltd	C8-966	107	2024.05.12	2027.05.11	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

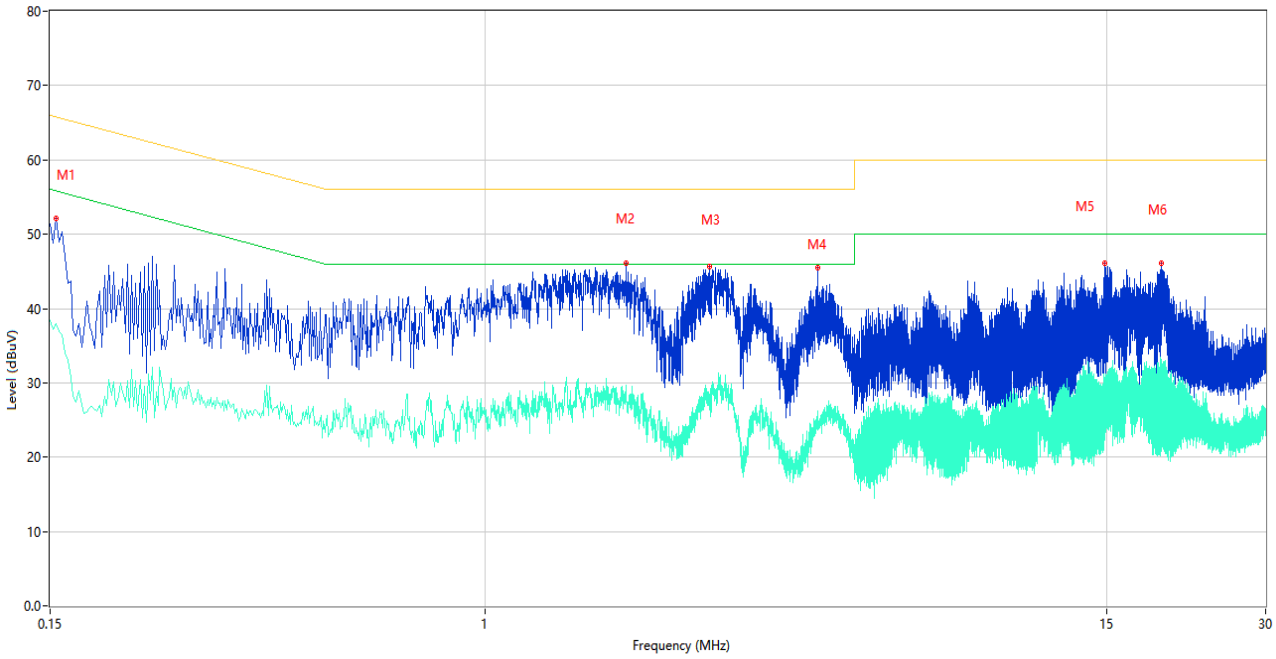
A.2 Conducted Emission, AC Ports

Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.

Sample No.	S15	Temperature	21.3℃
Humidity	55%RH	Pressure	100.3kPa
Test Engineer	Ye Xuanwei	Test Date	2026.07.29

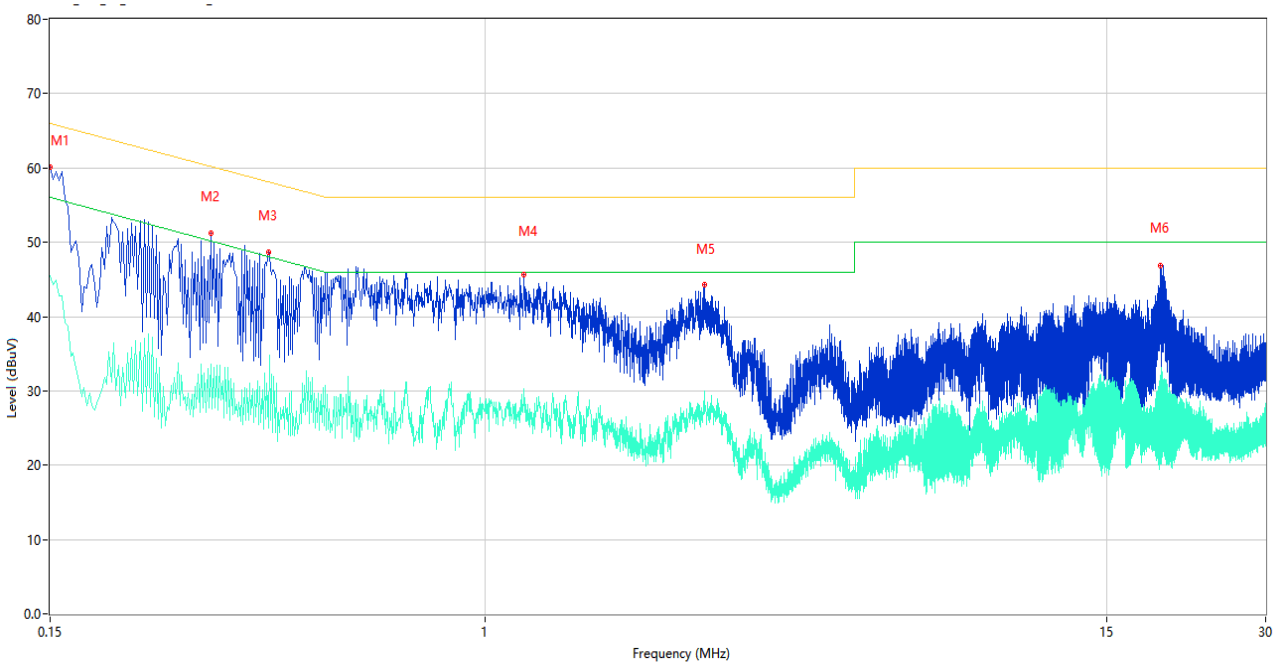
Test Mode 1

1) AC Ports - L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.154	52.16	10.23	65.78	13.62	Peak	L	Pass
1**	0.154	37.94	10.23	55.78	17.84	AV	L	Pass
2	1.850	46.17	10.43	56.00	9.83	Peak	L	Pass
2**	1.850	27.40	10.43	46.00	18.60	AV	L	Pass
3	2.656	45.62	10.56	56.00	10.38	Peak	L	Pass
3**	2.656	28.47	10.56	46.00	17.53	AV	L	Pass
4	4.262	45.46	10.92	56.00	10.54	Peak	L	Pass
4**	4.262	24.07	10.92	46.00	21.93	AV	L	Pass
5	14.886	46.15	13.83	60.00	13.85	Peak	L	Pass
5**	14.886	26.07	13.83	50.00	23.93	AV	L	Pass
6	19.016	46.04	14.83	60.00	13.96	Peak	L	Pass
6**	19.016	33.18	14.83	50.00	16.82	AV	L	Pass

2) AC Ports - N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.150	59.99	10.23	66.00	6.01	Peak	N	Pass
1**	0.150	45.39	10.23	56.00	10.61	AV	N	Pass
2	0.302	51.20	10.22	60.19	8.99	Peak	N	Pass
2**	0.302	33.53	10.22	50.19	16.66	AV	N	Pass
3	0.388	48.65	10.23	58.11	9.46	Peak	N	Pass
3**	0.388	24.95	10.23	48.11	23.16	AV	N	Pass
4	1.182	45.65	10.31	56.00	10.35	Peak	N	Pass
4**	1.182	28.63	10.31	46.00	17.37	AV	N	Pass
5	2.602	44.23	10.53	56.00	11.77	Peak	N	Pass
5**	2.602	29.95	10.53	46.00	16.05	AV	N	Pass
6	18.994	46.79	14.91	60.00	13.21	Peak	N	Pass
6**	18.994	21.22	14.91	50.00	28.78	AV	N	Pass

Equipment Information						
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9038B	MY61380132	2025.12.26	2026.12.25	☒
LISN	SCHWARZBECK	NSLK 8127	01009	2026.06.22	2027.06.21	☒
Shielded Room	YiHeng Electronic Co., Ltd	/	235	2024.11.05	2027.11.04	☒
Description	Supplier	Name	Version	/		Use
Test Software	BALUN	BL410-E	V22.4 en	/		☒

ANNEX B TEST SETUP PHOTOS

Please refer the document “Ti-CC26060432-AE-1.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “Ti-CC26060432-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “Ti-CC26060432-AI.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
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--END OF REPORT--